



PH955L

N-channel TrenchMOS™ logic level FET

Rev. 01 — 1 March 2005

Product data sheet

1. Product profile

1.1 General description

Logic level N-channel enhancement mode Field Effect Transistor (FET) in a plastic package using TrenchMOS™ technology.

1.2 Features

- Logic level threshold
- Very low on-state resistance

1.3 Applications

- DC-to-DC converters
- Motors, lamps and solenoids
- General purpose power switching
- Portable appliances

1.4 Quick reference data

- $V_{DS} \leq 55$ V
- $I_D \leq 62.5$ A
- $R_{DSon} \leq 8.3$ m Ω
- $Q_{gd} = 16.4$ nC (typ)

2. Pinning information

Table 1: Pinning

Pin	Description	Simplified outline	Symbol
1, 2, 3	source (S)		
4	gate (G)		
mb	mounting base; connected to drain (D)		

SOT669 (LFPACK)

PHILIPS

3. Ordering information

Table 2: Ordering information

Type number	Package		Version
	Name	Description	
PH955L	LFAK	plastic single-ended surface mounted package; 4 leads	SOT669

4. Limiting values

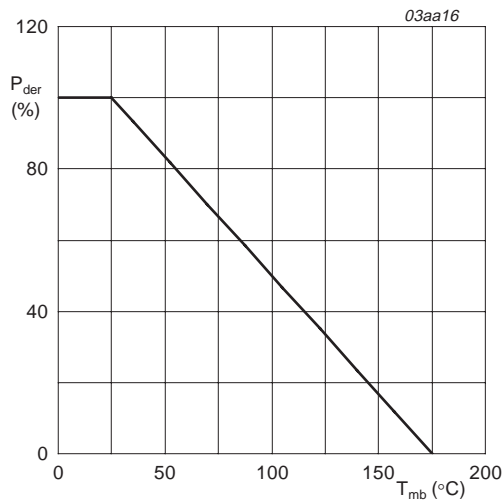
Table 3: Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage (DC)	$25\text{ °C} \leq T_j \leq 150\text{ °C}$	-	55	V
V_{DGR}	drain-gate voltage (DC)	$25\text{ °C} \leq T_j \leq 150\text{ °C}$; $R_{GS} = 20\text{ k}\Omega$	-	55	V
V_{GS}	gate-source voltage		-	± 20	V
I_D	drain current (DC)	$T_{mb} = 25\text{ °C}$; $V_{GS} = 5\text{ V}$; Figure 2 and Figure 3	-	62.5	A
		$T_{mb} = 100\text{ °C}$; $V_{GS} = 5\text{ V}$; Figure 2	-	43.7	A
I_{DM}	peak drain current	$T_{mb} = 25\text{ °C}$; pulsed; $t_p \leq 10\text{ }\mu\text{s}$; Figure 3	-	187	A
P_{tot}	total power dissipation	$T_{mb} = 25\text{ °C}$; Figure 1	-	62.5	W
T_{stg}	storage temperature		-55	+150	°C
T_j	junction temperature		-55	+150	°C
Source-drain diode					
I_S	source (diode forward) current (DC)	$T_{mb} = 25\text{ °C}$	-	52	A
I_{SM}	peak source (diode forward) current	$T_{mb} = 25\text{ °C}$; pulsed; $t_p \leq 10\text{ }\mu\text{s}$	-	156	A
Avalanche ruggedness					
$E_{DS(AL)S}$	non-repetitive drain-source avalanche energy	unclamped inductive load; $I_D = 44\text{ A}$; $t_p = 0.1\text{ ms}$; $V_{DD} \leq 55\text{ V}$; $R_{GS} = 50\text{ }\Omega$; $V_{GS} = 5\text{ V}$; starting at $T_j = 25\text{ °C}$	-	195	mJ
$E_{DS(AL)R}$	repetitive drain-source avalanche energy	unclamped inductive load; $I_D = 4.4\text{ A}$; $t_p = 0.1\text{ ms}$; $V_{DD} \leq 55\text{ V}$; $R_{GS} = 50\text{ }\Omega$; $V_{GS} = 5\text{ V}$	[1] - [2]	2	mJ

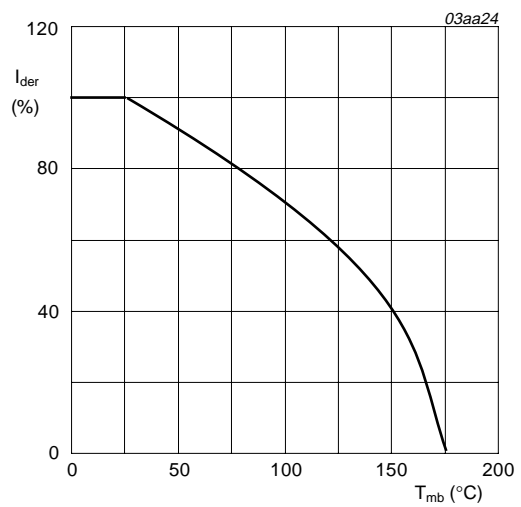
[1] Duty cycle is limited by the maximum junction temperature.

[2] Repetitive avalanche failure is not determined simply by thermal effects. Repetitive avalanche transients should only be applied for short bursts, not every switching cycle.



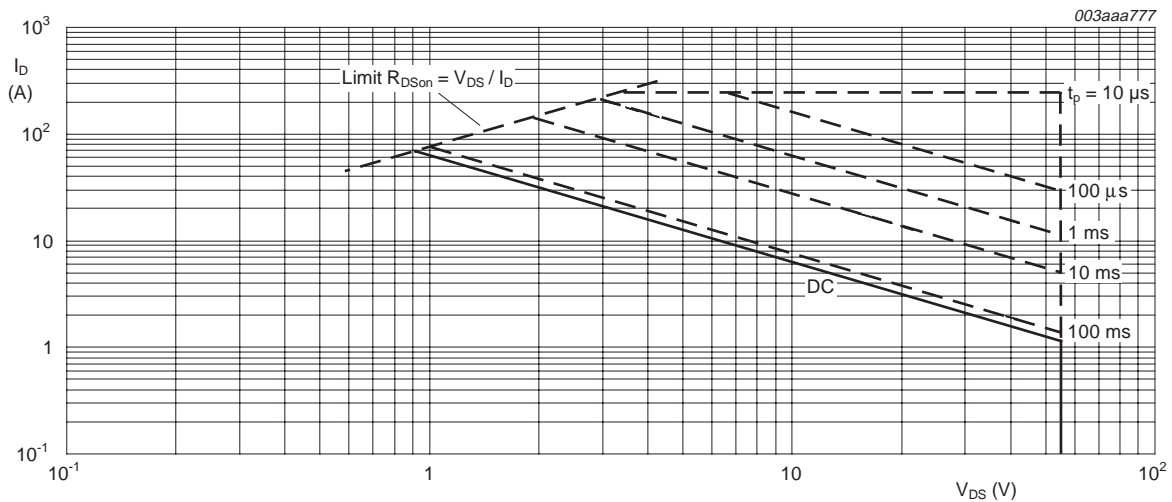
$$P_{der} = \frac{P_{tot}}{P_{tot(25^\circ C)}} \times 100 \%$$

Fig 1. Normalized total power dissipation as a function of mounting base temperature



$$I_{der} = \frac{I_D}{I_{D(25^\circ C)}} \times 100 \%$$

Fig 2. Normalized continuous drain current as a function of mounting base temperature



T_{mb} = 25 °C; I_{DM} is single pulse; V_{GS} = 10 V

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

5. Thermal characteristics

Table 4: Thermal characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	Figure 4	-	-	2	K/W

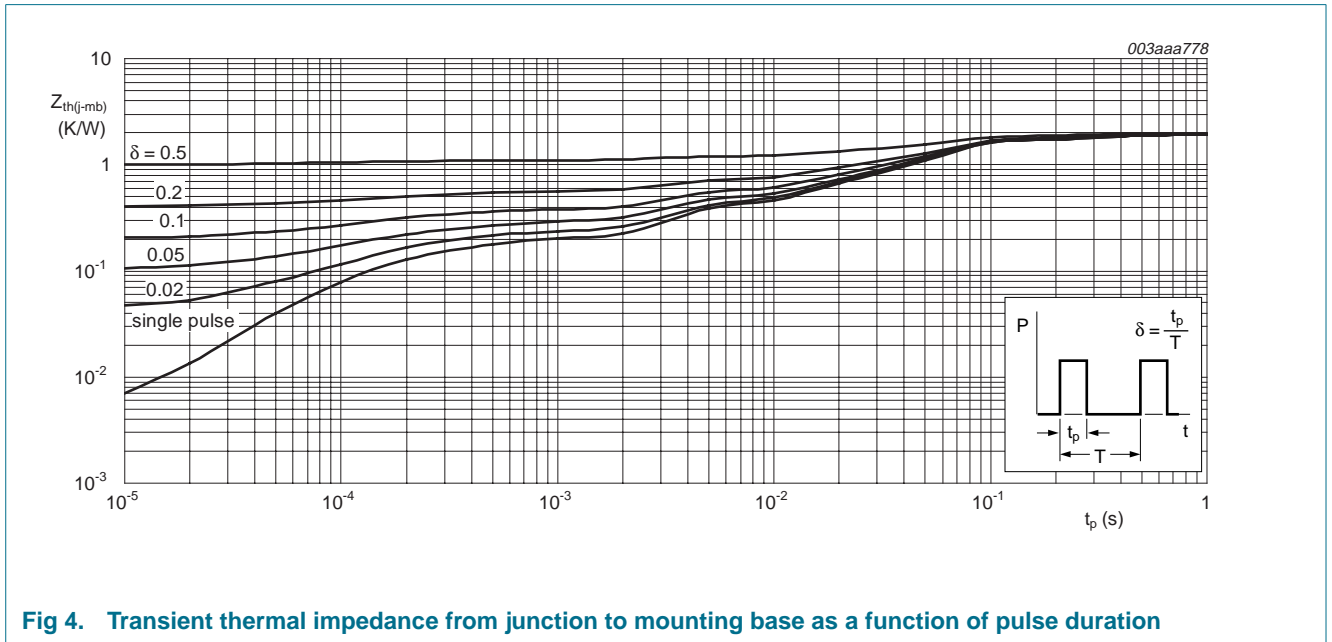


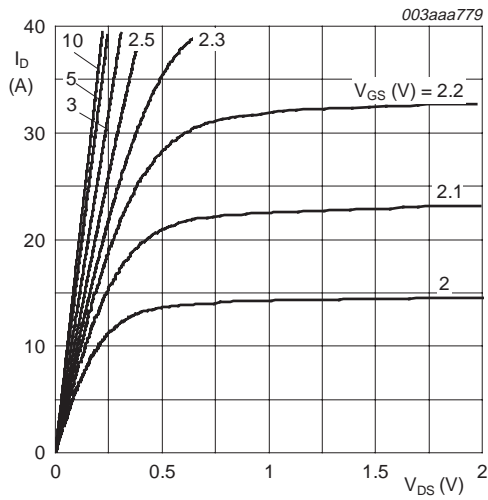
Fig 4. Transient thermal impedance from junction to mounting base as a function of pulse duration

6. Characteristics

Table 5: Characteristics

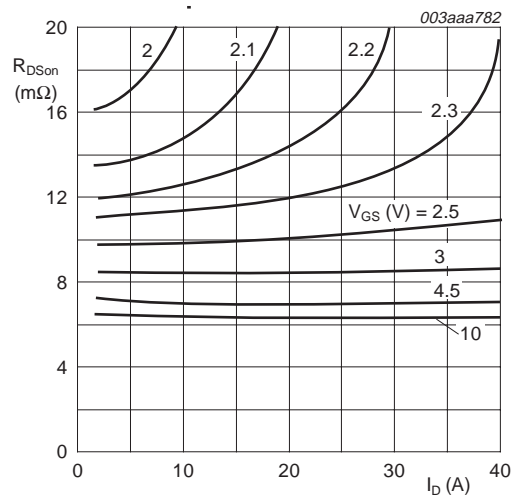
$T_j = 25\text{ °C}$ unless otherwise specified.

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Static characteristics						
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = 250\ \mu\text{A}$; $V_{GS} = 0\ \text{V}$				
		$T_j = 25\text{ °C}$	55	-	-	V
		$T_j = -55\text{ °C}$	50	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1\ \text{mA}$; $V_{DS} = V_{GS}$; Figure 9 and 10				
		$T_j = 25\text{ °C}$	1	1.5	2	V
		$T_j = 150\text{ °C}$	0.5	-	-	V
		$T_j = -55\text{ °C}$	-	-	2.3	V
I_{DSS}	drain-source leakage current	$V_{DS} = 55\ \text{V}$; $V_{GS} = 0\ \text{V}$				
		$T_j = 25\text{ °C}$	-	0.02	1	μA
		$T_j = 150\text{ °C}$	-	-	500	μA
I_{GSS}	gate-source leakage current	$V_{GS} = \pm 15\ \text{V}$; $V_{DS} = 0\ \text{V}$	-	2	100	nA
$R_{DS(on)}$	drain-source on-state resistance	$V_{GS} = 10\ \text{V}$; $I_D = 25\ \text{A}$				
		$T_j = 25\text{ °C}$; Figure 6	-	6.2	8.3	m Ω
		$T_j = 150\text{ °C}$; Figure 8	-	-	16	m Ω
		$V_{GS} = 4.5\ \text{V}$; $I_D = 25\ \text{A}$	-	7.1	9.9	m Ω
Dynamic characteristics						
$Q_{g(tot)}$	total gate charge	$I_D = 25\ \text{A}$; $V_{DD} = 44\ \text{V}$; $V_{GS} = 5\ \text{V}$; Figure 11 and Figure 12	-	42	-	nC
Q_{gs}	gate-source charge		-	5.7	-	nC
Q_{gs1}	pre- $V_{GS(th)}$ gate-source charge		-	4.3	-	nC
Q_{gs2}	post- $V_{GS(th)}$ gate-source charge		-	1.4	-	nC
Q_{gd}	gate-drain (Miller) charge		-	16.4	-	nC
V_{plat}	plateau voltage		-	2	-	V
C_{iss}	input capacitance	$V_{GS} = 0\ \text{V}$; $V_{DS} = 25\ \text{V}$; $f = 1\ \text{MHz}$; Figure 14	-	2 836	-	pF
C_{oss}	output capacitance		-	441	-	pF
C_{rss}	reverse transfer capacitance		-	210	-	pF
$t_{d(on)}$	turn-on delay time	$V_{DS} = 25\ \text{V}$; $R_L = 1\ \Omega$; $V_{GS} = 5\ \text{V}$; $R_G = 4.7\ \Omega$	-	18	-	ns
t_r	rise time		-	71	-	ns
$t_{d(off)}$	turn-off delay time		-	105	-	ns
t_f	fall time		-	25	-	ns
Source-drain diode						
V_{SD}	source-drain (diode forward) voltage	$I_S = 25\ \text{A}$; $V_{GS} = 0\ \text{V}$; Figure 13	-	0.85	1.2	V
t_{rr}	reverse recovery time	$I_S = 20\ \text{A}$; $dI_S/dt = -100\ \text{A}/\mu\text{s}$;	-	62	-	ns
Q_r	recovered charge	$V_{GS} = 0\ \text{V}$; $V_R = 30\ \text{V}$	-	48	-	nC



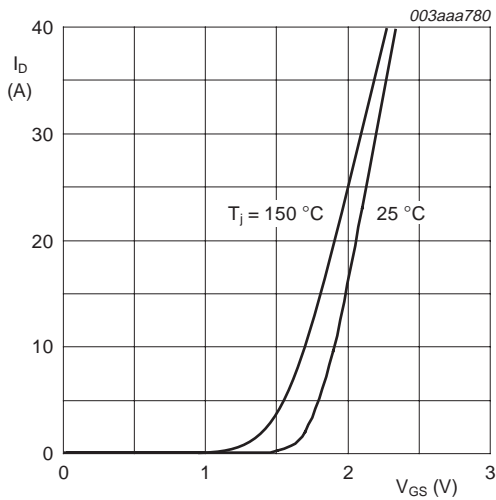
$T_j = 25^\circ\text{C}$

Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values



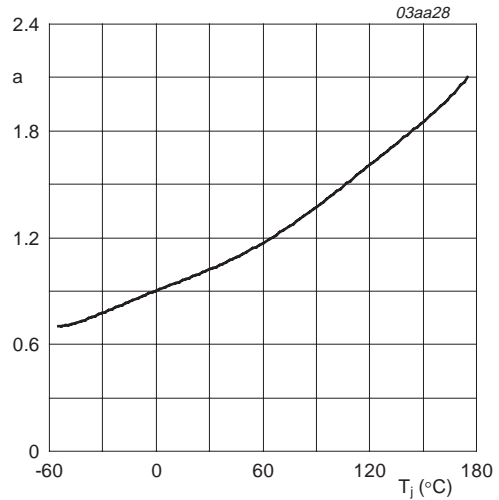
$T_j = 25^\circ\text{C}$

Fig 6. Drain-source on-state resistance as a function of drain current; typical values



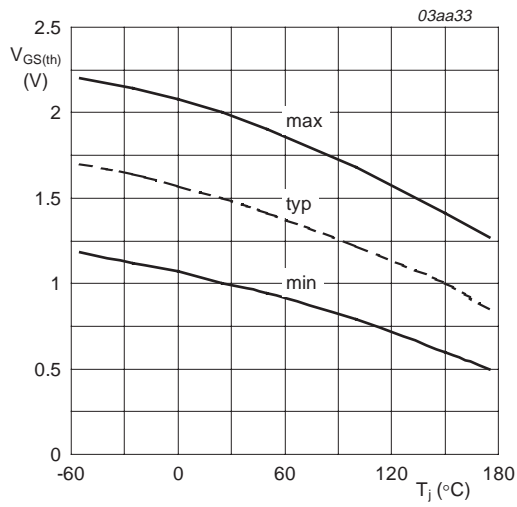
$T_j = 25^\circ\text{C}$ and 150°C ; $V_{DS} > I_D \times R_{DS(on)}$

Fig 7. Transfer characteristics: drain current as a function of gate-source voltage; typical values



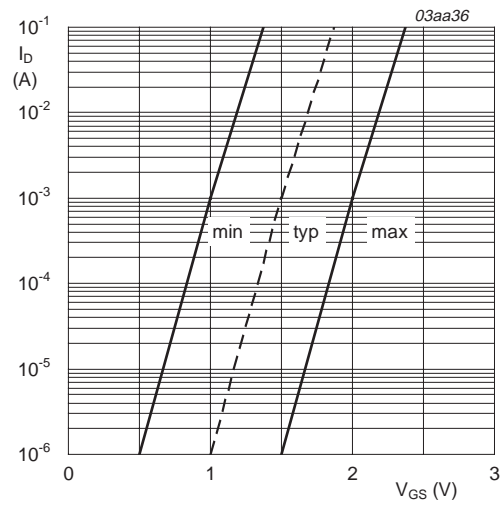
$$a = \frac{R_{DS(on)}}{R_{DS(on)(25^\circ\text{C})}}$$

Fig 8. Normalized drain-source on-state resistance factor as a function of junction temperature



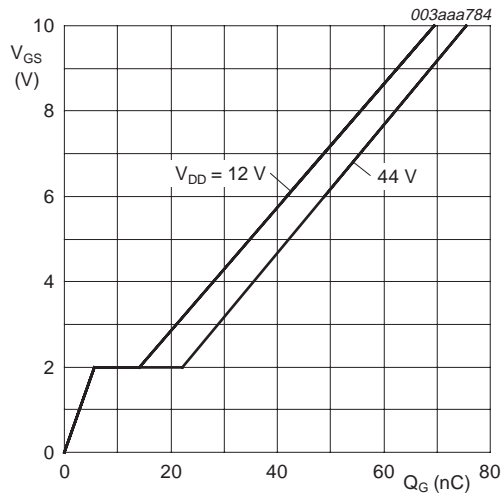
$I_D = 1 \text{ mA}; V_{DS} = V_{GS}$

Fig 9. Gate-source threshold voltage as a function of junction temperature



$T_j = 25 \text{ }^\circ\text{C}; V_{DS} = 5 \text{ V}$

Fig 10. Sub-threshold drain current as a function of gate-source voltage



$I_D = 25 \text{ A}; V_{DD} = 12 \text{ V and } 44 \text{ V}$

Fig 11. Gate-source voltage as a function of gate charge; typical values

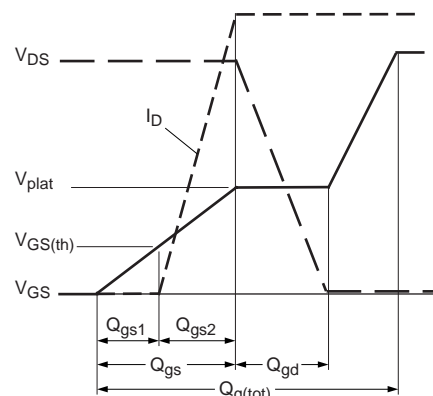
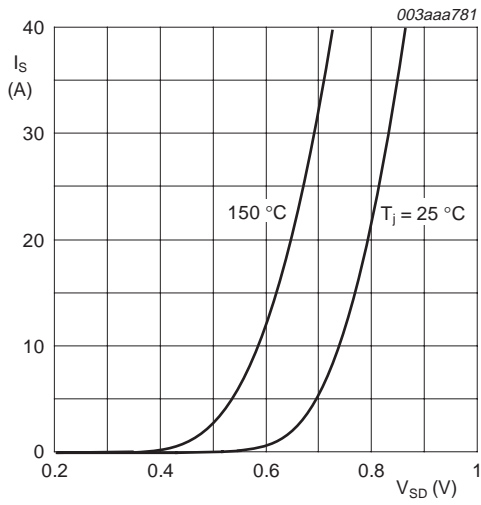
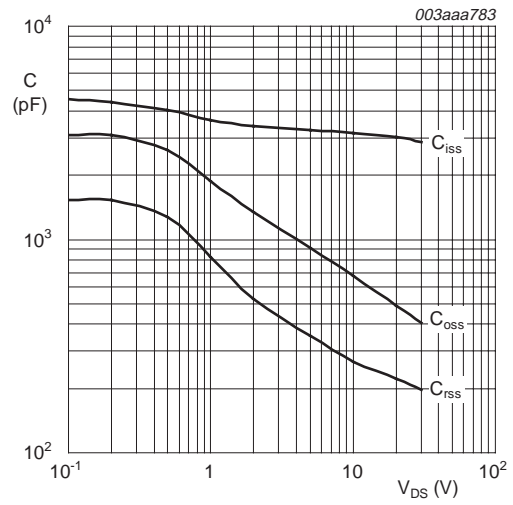


Fig 12. Gate charge waveform definitions



$T_j = 25^\circ\text{C}$ and 150°C ; $V_{GS} = 0\text{ V}$

Fig 13. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values



$V_{GS} = 0\text{ V}$; $f = 1\text{ MHz}$

Fig 14. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

7. Package outline

Plastic single-ended surface mounted package (LPAK); 4 leads

SOT669

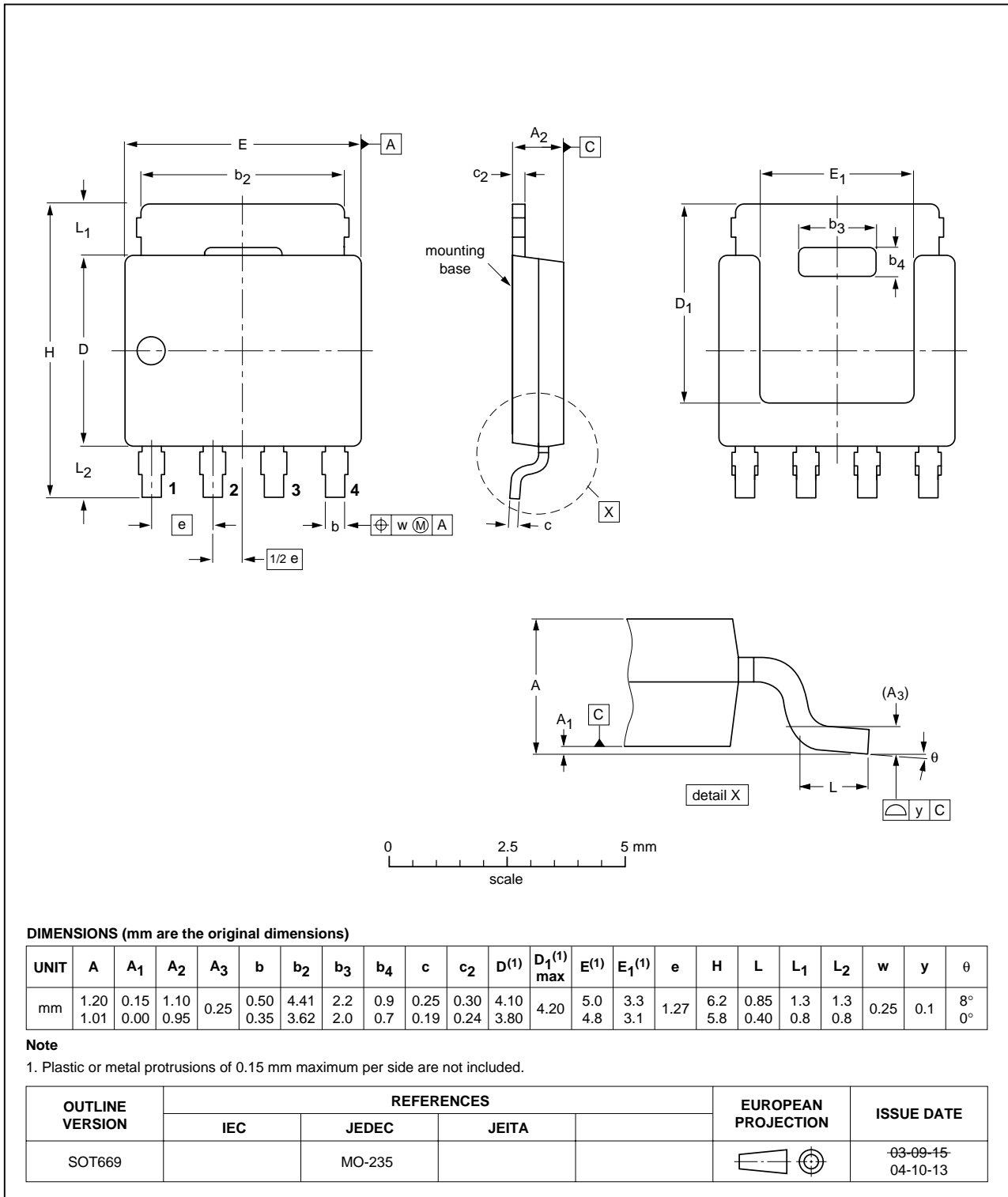


Fig 15. Package outline SOT669 (LPAK)

8. Revision history

Table 6: Revision history

Document ID	Release date	Data sheet status	Change notice	Doc. number	Supersedes
PH955L_1	20050301	Product data sheet	-	9397 750 14557	-

9. Data sheet status

Level	Data sheet status ^[1]	Product status ^{[2] [3]}	Definition
I	Objective data	Development	This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice.
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